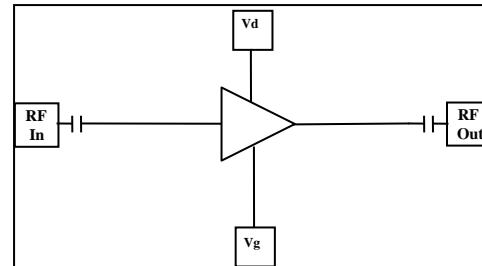


## 5 – 6 GHz 20dBm Gain block Amplifier

### Features

- ◆ Frequency Range : 5 – 6GHz
- ◆ 21.5 dBm output P1dB
- ◆ 14 dB Power gain
- ◆ 30% PAE
- ◆ High IP3
- ◆ Input Return Loss > 12 dB
- ◆ Output Return Loss > 15 dB
- ◆ Dual bias operation
- ◆ No external matching required
- ◆ DC decoupled input and output
- ◆ 0.5  $\mu\text{m}$  InGaAs pHEMT Technology
- ◆ Chip dimension: 1.2 x 1.6 x 0.1 mm

### Functional Diagram



### Typical Applications

- ◆ RADAR
- ◆ Military & space
- ◆ LMDS, VSAT

### Description

The ASL4026 is a C-band Gain block amplifier with 20dBm power output. The PA operates in 5 – 6 GHz frequency range. The PA features 14 dB of gain with input and output return losses of 12 dB and 15 dB respectively. The PA has a high IP3 of 30dBm and 35% PAE. This feature enables it to be used in the applications requiring efficiency along with linearity. The chip operates with dual bias supply voltage. The die is fabricated using a reliable 0.5 $\mu\text{m}$  InGaAs pHEMT technology. The Circuit grounds are provided through vias to the backside metallization.

### Absolute Maximum Ratings <sup>(1)</sup>

Parameter	Absolute Maximum	Units
Drain bias voltage (Vd)	+8	volts
Drain current (Idq)	120	mA
RF input power (RFIn at Vd=9V)	23	dBm
Operating temperature	-50 to +85	°C
Storage Temperature	-65 to +150	°C

1. Operation beyond these limits may cause permanent damage to the component

**Electrical Specifications <sup>(1)</sup> @ T<sub>A</sub> = 25 °C, V<sub>d</sub> = 8V, V<sub>g</sub> = -0.9V, Z<sub>o</sub> = 50 Ω**

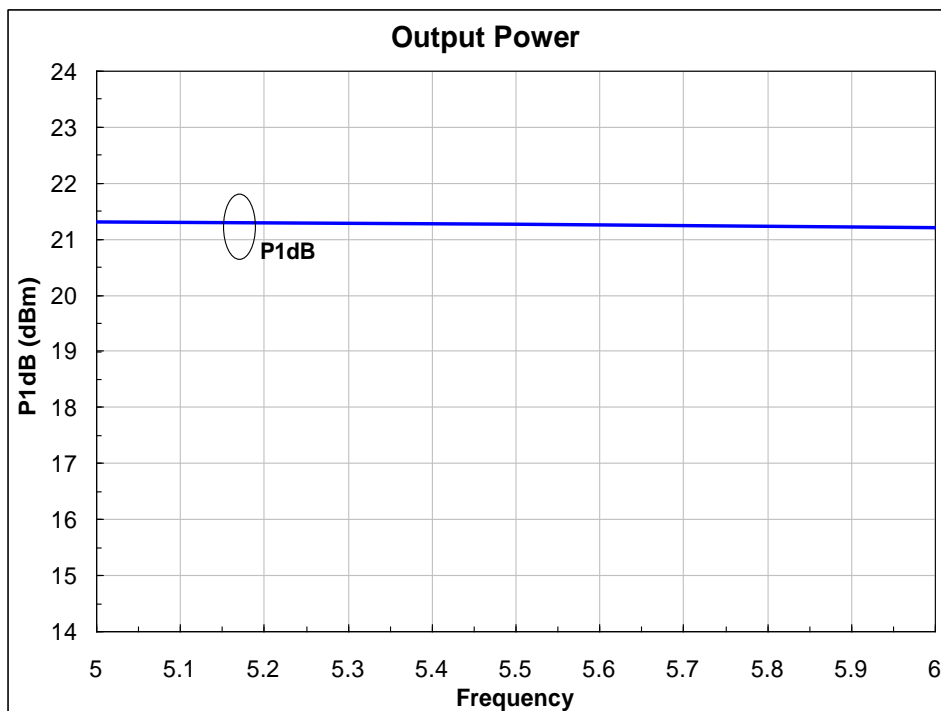
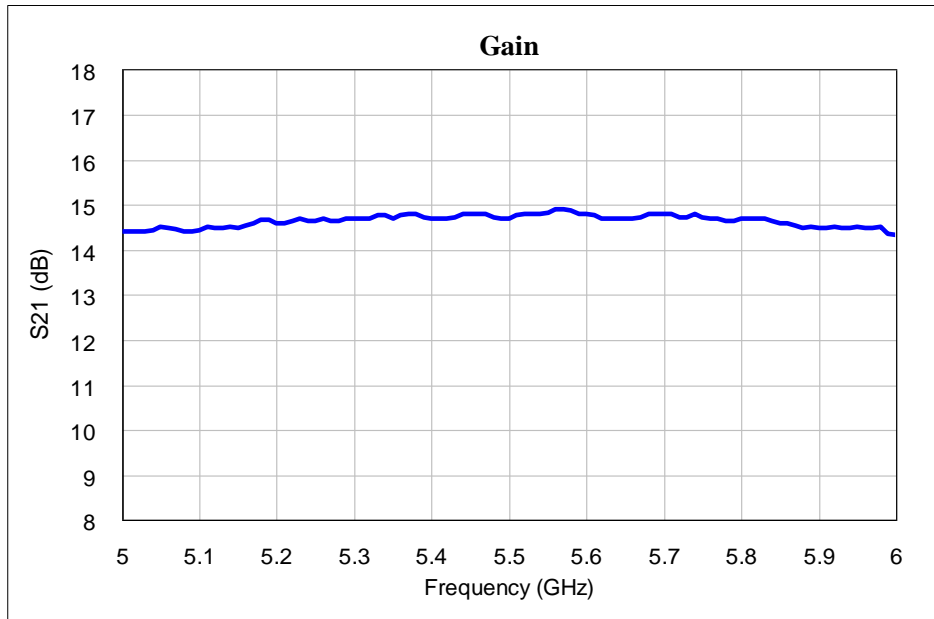
Parameter	Typ.	Units
Frequency Range	5 – 6	GHz
Gain	14	dB
Gain Flatness	+/-0.3	dB
Output Power (P1 dB)	21.5	dBm
Input Return Loss	12	dB
Output Return Loss	15	dB
Saturated output power (P <sub>sat</sub> )	22.5	dBm
Output Third Order Intercept (IP3)	30	dBm
Power Added Efficiency (PAE)	30%	--
Supply Current(I <sub>dq</sub> )	60	mA

**Note:**

1. Electrical specifications as measured in test fixture.

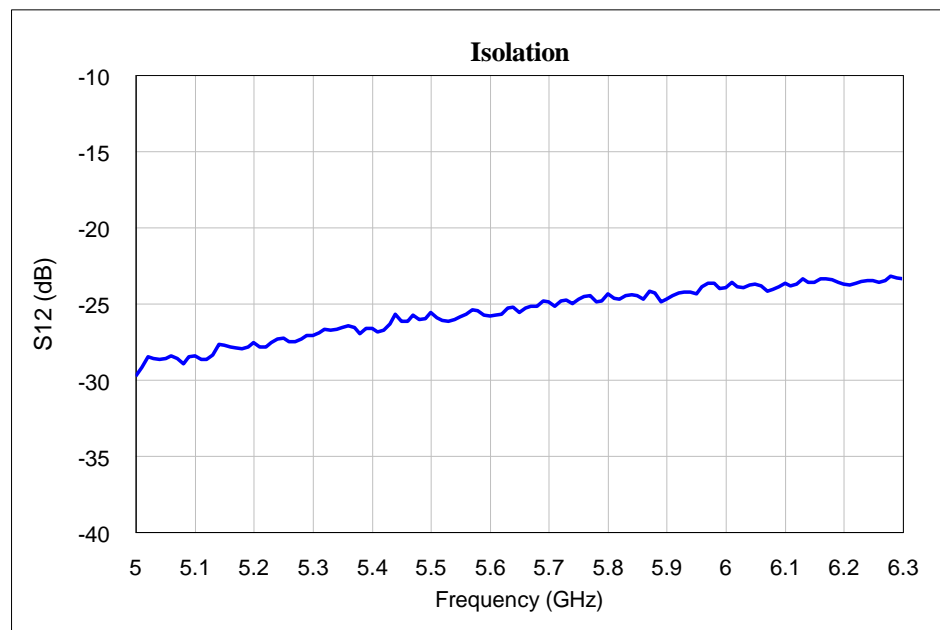
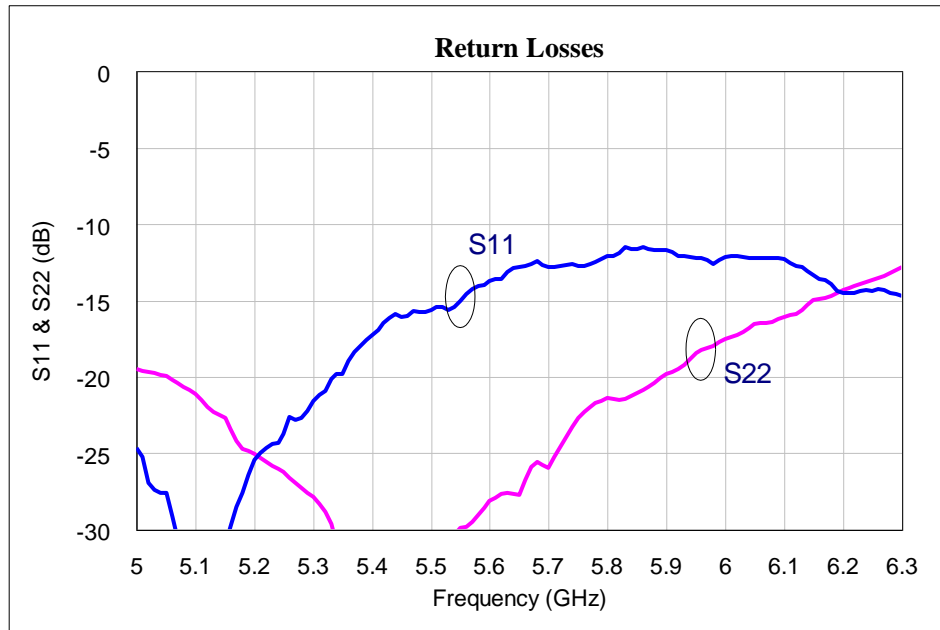
**Test fixture data**

$V_d = 8V$ ,  $V_g = -0.9V$ , Total Current = 60ma,  $T_A = 25^\circ C$

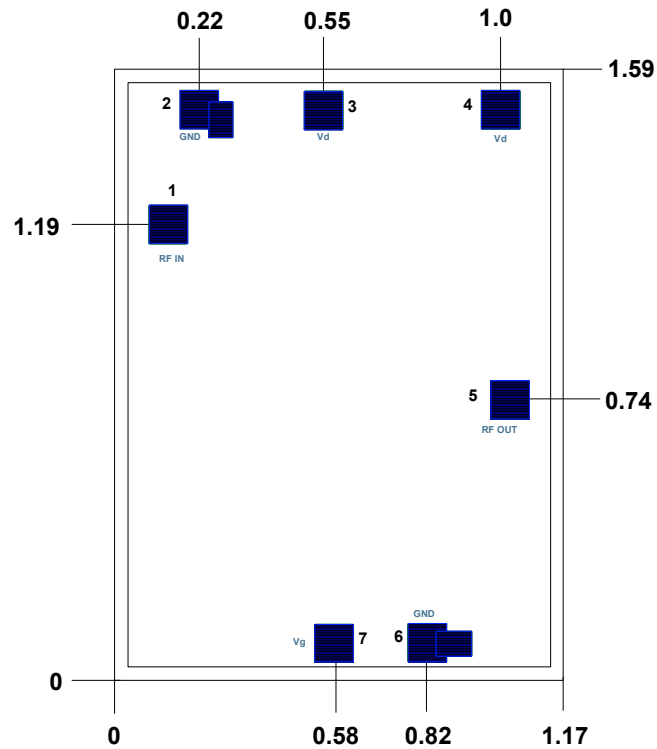


**Test fixture data**

$V_d = 8V$ ,  $V_g = -0.9V$ , Total Current = 60ma,  $T_A = 25^\circ C$



## Bond Pad Locations

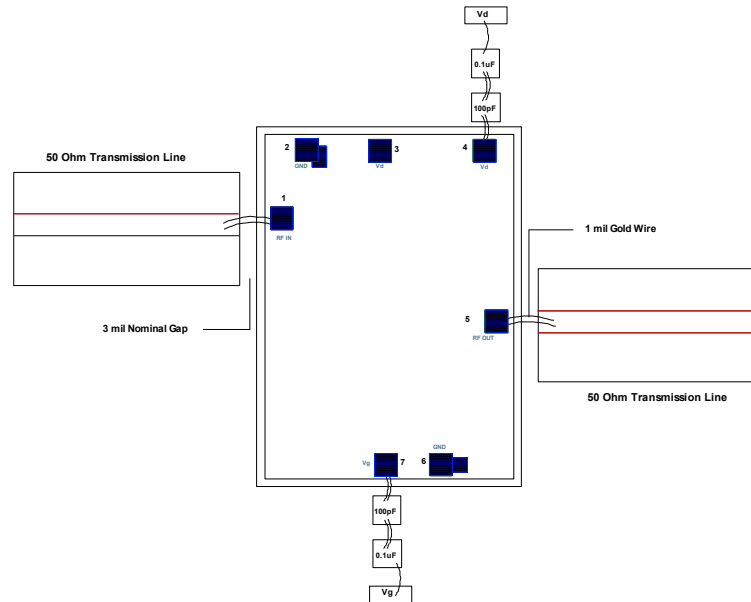


**Units:** millimeters

**Note:**

1. All RF and DC bond pads are 100 $\mu$ m x 100 $\mu$ m
2. Pad no. 1 : RF IN
3. Pad no. 4 : Drain voltage( $V_d$ )
4. Pad no. 5 : RF Output
5. Pad no. 7 : Gate voltage ( $V_g$ )

## Recommended Assembly Diagram



### Note:

1. Two 1 mil (0.0254mm) bond wires of minimum length should be used for RF input and output.
2. Two 1 mil (0.0254mm) bond wires of minimum length should be used from chip bond pad to 100pF capacitor.
3. Input and output 50 ohm lines are on 5 mil RT Duroid substrate
4. 0.1  $\mu$ F capacitors may be additionally used as a second level of bypass for reliable operation
5. The RF input & output ports are DC decoupled on-chip.
6. Proper heat sink like Copper tungsten or copper molybdenum to be used for better reliability of chip

**Die attach:** For Epoxy attachment, use of a two-component conductive epoxy is recommended. An epoxy fillet should be visible around the total die periphery. If Eutectic attachment is preferred, use of fluxless AuSn (80/20) 1-2 mil thick preform solder is recommended. Use of AuGe preform should be strictly avoided.

**Wire bonding:** For DC pad connections use either ball or wedge bonds. For best RF performance, use of 150 - 200 $\mu$ m length of wedge bonds is advised. Single Ball bonds of 250-300 $\mu$ m though acceptable, may cause a deviation in RF performance.



***GaAs MMIC devices are susceptible to Electrostatic discharge. Proper precautions should be observed during handling, assembly & testing***

All information and Specifications are subject to change without prior notice